


<b>Search Notes</b>  	<b>Application/Control No.</b>  10526565	<b>Applicant(s)/Patent Under Reexamination</b>  NAGHIAN, SIAMAK
	<b>Examiner</b>  Pablo N Tran	<b>Art Unit</b>  2618

SEARCHED			
Class	Subclass	Date	Examiner
370	255, 229-230, 235, 238, 252-256, 310.1-313, 328, 338, 386-393, 432	3/30/08	PT
455	403, 418-425, 432.1, 434-445, 450-456.1	3/30/08	PT

SEARCH NOTES		
Search Notes	Date	Examiner
East/West	3/30/08	PT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner